

Notice of References Cited

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Application/Control No.	Applicant(s)/Pater	nt Under
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Examiner	Art Unit	
Oanh L. Duong	2155	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,466,966	10-2002	Kirsch et al.	709/203
	В	US-			
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	J	US-			
	К	US-			
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NON-PATENT DOCUMENTS

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